

ECE 266 Lab2 Design Review

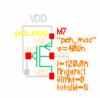
Mingjie Ma Chengming Li

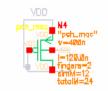
University of California, San Diego, La Jolla, CA, USA

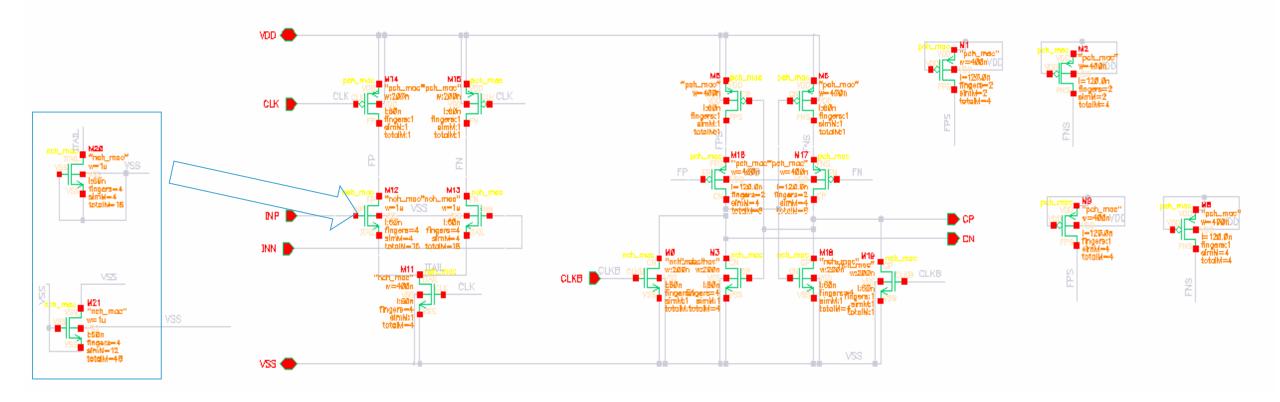


Schematic

Dummy Devices for M12 and M13: Top+bottom(DGS are shorted to VSS): 4fin * 12m * 1u Left+Right(D-Itail, GS are shorted to VSS): 4fin * 4m *1u









Comparator Layout

Common Centroid Pattern

ABBA

BAAB

After dummy devices

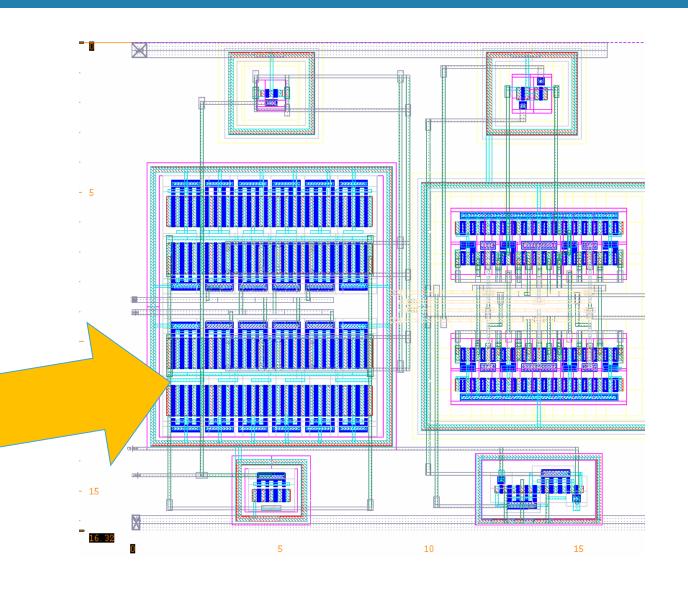
(D:2 fingers; d: 1fingers)

DDDDDD

DABBAD

DBAABD

DDDDDD





Schematic

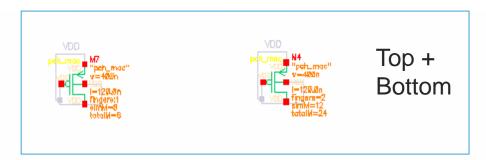
Dummy Devices for M17 and M18:

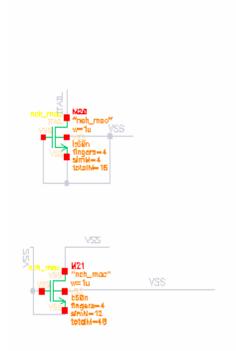
*Top Bottom(DGS - VDD): 1fin * 8m * 400n

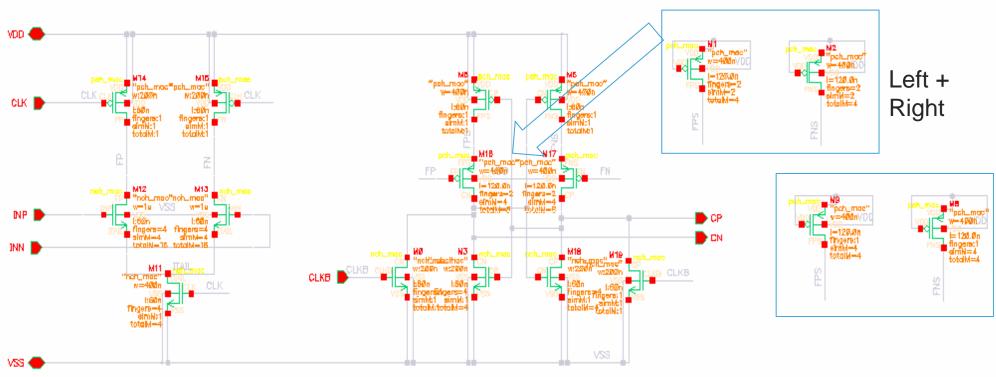
2fin * 12m * 400n

Left+Right(GS- VDD, D- FNS/FPS): 1fin * 8m *400n

2fin * 4m * 400n









Comparator Layout

Common Centroid Pattern

ABBA

BAAB

After dummy devices

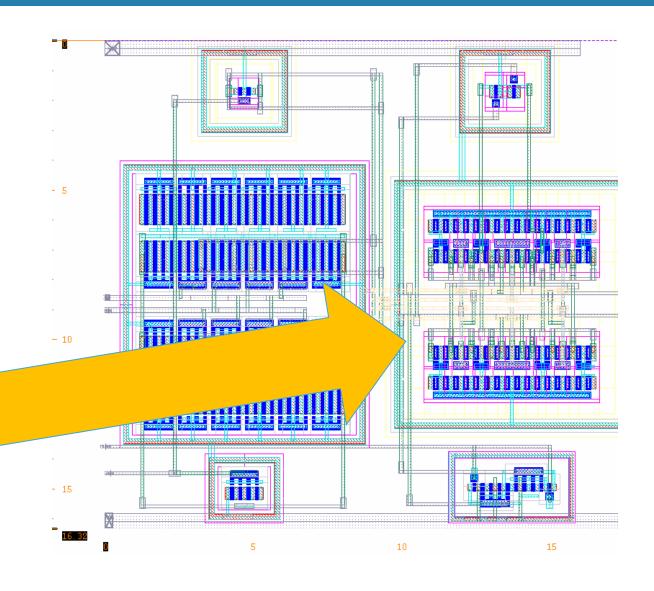
(D:2 fingers; d: 1fingers)

DDddDDddDD

DAddBBddAD

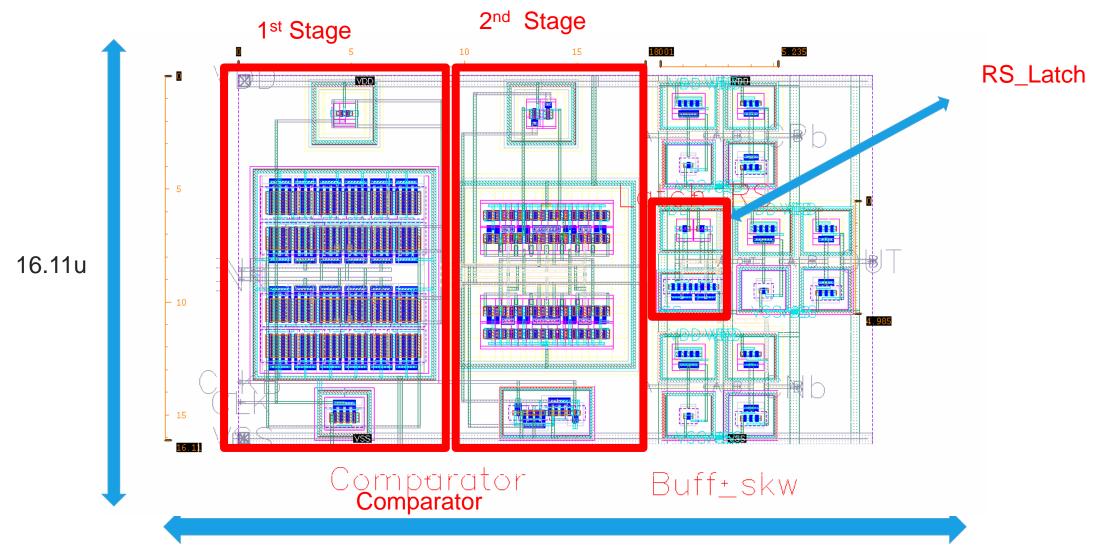
DBddAAddBD

DDddDDddDD



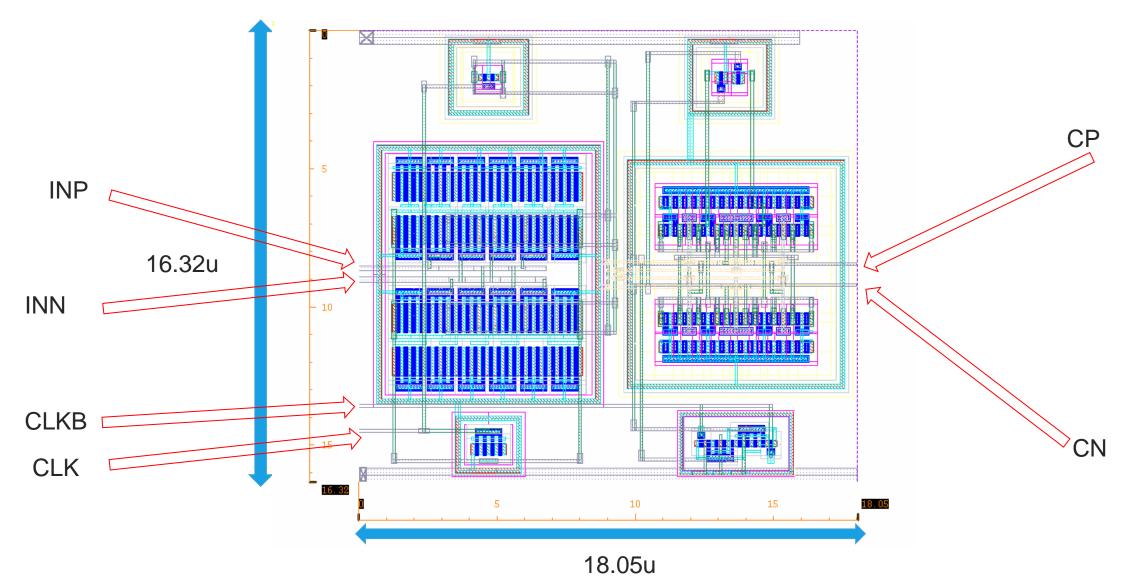


Top Level Layout



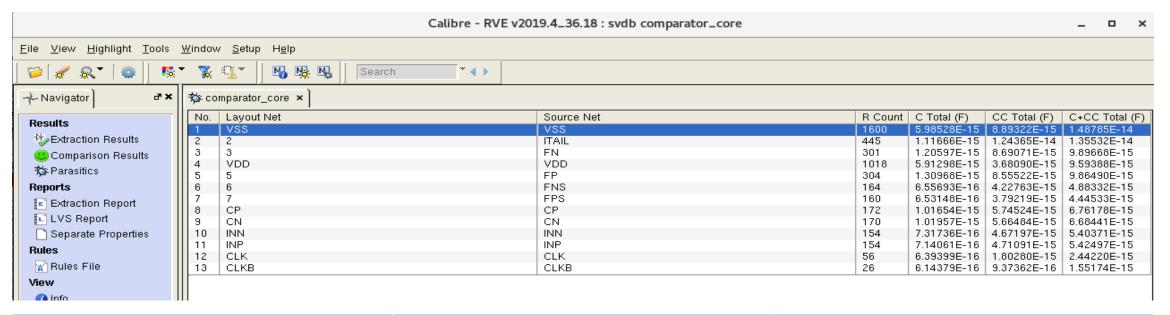


Comparator Layout





RCX Cap Table



Source Net	C+CC (F)	Difference(%)
FP	9.8649f	
FN	9.89668f	-0.32%
CP	6.76178f	
CN	6.68441f	1.144%
INP	5.42497f	
INN	5.40371f	0.39%



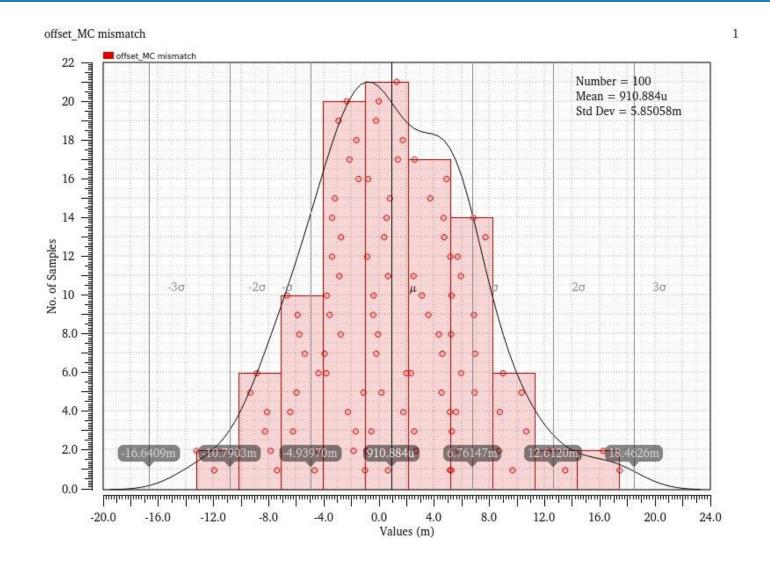
Extracted Simulation(Offset) – Process Corners

	Parameter						TT	FF	SS
	crn65gplus_2d5						tt_lvt	ff_lvt	ss_lvt
	crn65gplus_2d5						tt	ff	SS
	temperature				_		27	27	27
Test	Output	Spec	Weight	Pass/Fail	Min	Max	TT	FF	SS
Lab2_copy:comp_off_TB:3	/INN						<u></u>	<u></u>	<u>L</u>
Lab2_copy:comp_off_TB:3	/INP						<u></u>	<u></u>	<u>L</u>
Lab2_copy:comp_off_TB:3	/OUT						<u></u>	<u></u>	<u>L</u>
Lab2_copy:comp_off_TB:3	/CLK						<u></u>	<u></u>	<u>L</u>
Lab2_copy:comp_off_TB:3	/I0/CNb						<u></u>	<u></u>	<u>L</u>
Lab2_copy:comp_off_TB:3	/I0/CPb						<u></u>	<u></u>	<u>L</u>
Lab2_copy:comp_off_TB:3	/10/VDD						<u></u>	<u></u>	<u>L</u>
Lab2_copy:comp_off_TB:3	Pwr				1.168u	3.342u	1.484u	3.342u	1.168u
Lab2_copy:comp_off_TB:3	/OFF						<u></u>	<u></u>	<u>~</u>
Lab2_copy:comp_off_TB:3	offset				269.2u	740.4u	740.4u	269.2u	386.4u

Test Corners	TT	FF	SS
This work	740.4u	269.2	386.4u



Extracted Simulation(Offset) – Mismatch





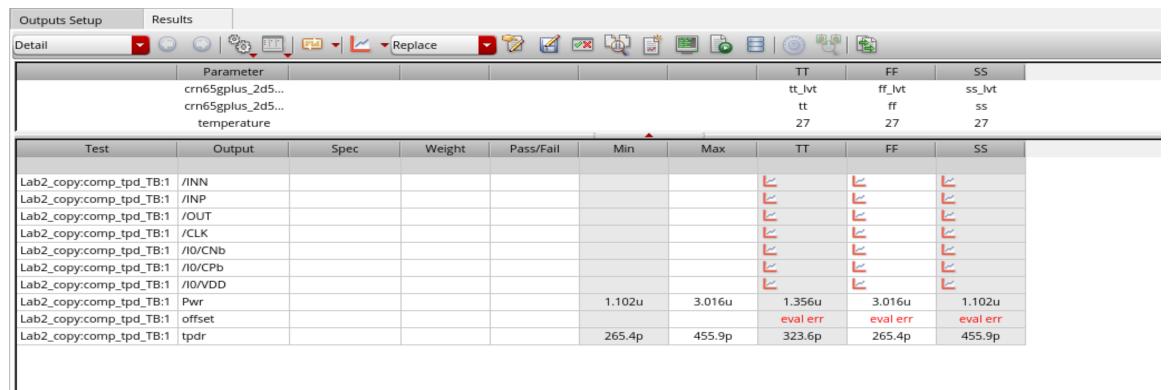
Extracted Simulation(Tpd) – Process Corners

	Parameter						TT	FF	SS
	crn65gplus_2d5						tt_lvt	ff_lvt	ss_lvt
	crn65gplus_2d5						tt	ff	SS
	temperature						27	27	27
Test	Output	Spec	Weight	Pass/Fail	Min	Max	TT	FF	SS
		·							
Lab2_combine:comp_tpd_TB:4	/INN						<u></u>	<u></u>	<u>Ľ</u>
Lab2_combine:comp_tpd_TB:4	/INP						<u></u>	<u></u>	<u>Ľ</u>
Lab2_combine:comp_tpd_TB:4	/OUT						<u></u>	<u></u>	<u>L</u>
Lab2_combine:comp_tpd_TB:4	/CLK						<u></u>	<u></u>	<u>Ľ</u>
Lab2_combine:comp_tpd_TB:4	/I0/CNb						<u></u>	<u></u>	<u>Ľ</u>
Lab2_combine:comp_tpd_TB:4	/10/CPb						<u></u>	<u></u>	<u>Ľ</u>
Lab2_combine:comp_tpd_TB:4	/10/VDD						<u></u>	<u></u>	<u>L</u>
Lab2_combine:comp_tpd_TB:4	Pwr				1.056u	2.921u	1.273u	2.921u	1.056u
Lab2_combine:comp_tpd_TB:4	offset						eval err	eval err	eval err
Lab2_combine:comp_tpd_TB:4	tpdr				270.5p	457.6p	322.4p	270.5p	457.6p

Test Corners	TT	FF	SS
Tpd(s)	322.4p	270.5p	457.6p



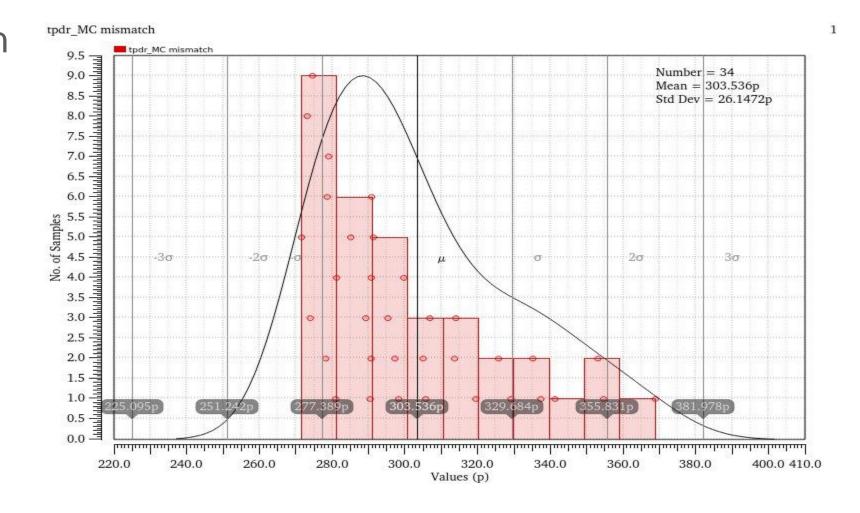
Extracted Simulation(Tpd) – Process Corners



Test Corners	TT	FF	SS
Tpd(s)	323.6p	265.4p	455.9p

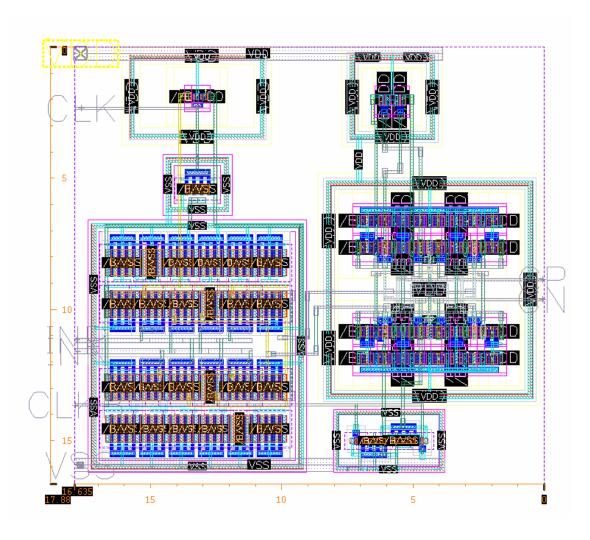


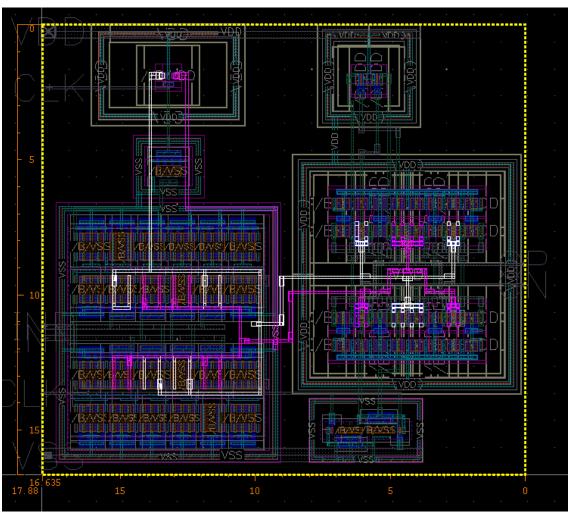
Extracted Simulation(Tpd) - Mismatch





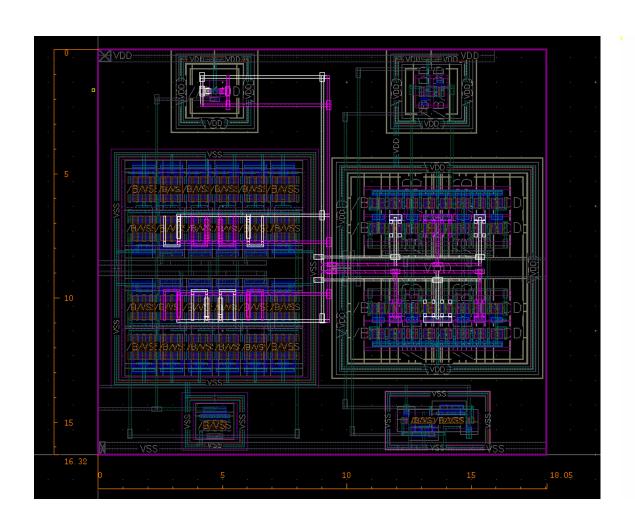
Appendix - #1 Iteration

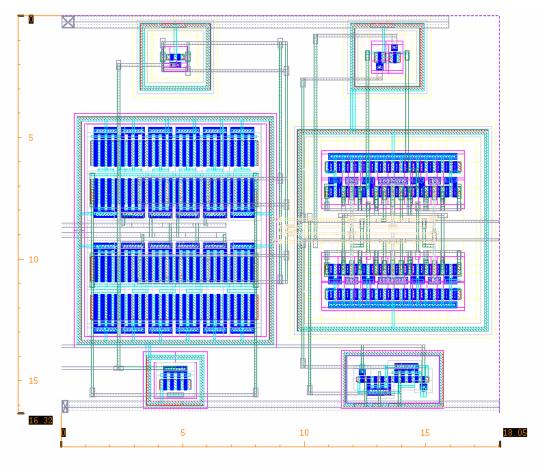






Appendix - #2 Iteration







Appendix – Metal Color

